Docket No.

239525US2

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF:

Yukio TANIGUCHI, et al.

SERIAL NO: New Application

GAU:

FILED:

Herewith

EXAMINER:

FOR:

CRYSTALLIZATION APPARATUS. OPTICAL MEMBER FOR USE IN CRYSTALLIZATION APPARATUS.

CRYSTALLIZATION METHOD, THIN FILM TRANSISTOR, AND DISPLAY

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

COMMISSIONER FOR PATENTS ALEXANDRIA, VIRGINIA 22313

SIR:

Applicant(s) wish to disclose the following information.

REFERENCES

- The applicant(s) wish to make of record the references listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.
- A check is attached in the amount required under 37 CFR §1.17(p).

RELATED CASES

- Attached is a list of applicant's pending application(s) or issued patent(s) which may be related to the present application. A copy of the patent(s), together with a copy of the claims and drawings of the pending application(s) is attached along with PTO 1449.
- ☐ A check is attached in the amount required under 37 CFR §1.17(p).

CERTIFICATION

- ☐ Each item of information contained in this information disclosure statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of
- ☐ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

DEPOSIT ACCOUNT

Please charge any additional fees for the papers being filed herewith and for which no check is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

OBLON, SPIVAK, McCLELLAND, MAIER & NEUSTADT, P.C.

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FOR: CRYSTALLIZATION APPARATUS, OPTICAL MEMBER FOR USE IN

CRYSTALLIZATION APPARATUS, CRYSTALLIZATION METHOD,

THIN FILM TRANSISTOR, AND DISPLAY

STATEMENT OF RELEVANCY

Reference AV and AW of Form PTO-1449:

This documents are disclosed in the body of the specification.

Form PTO 1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY DOCKET NO.		SERIAL NO. New Application			
(Modified)				239525US2					
LIST OF REFERENCES CITED BY APPLICANT			APPLICANT						
			Yukio TANIGUCHI, et al.						
				FILING DATE		GROUP			
				Herewith					
U.S. PATENT DOCUMENTS									
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)									
Masakiyo MATSUMURA, "PREPARATION OF ULTRA-LARGE GRAIN SILICON THIN-FILMS BY EXCIMER-LASER",									
	AV Surface Science, Vol. 21, No. 5, pp. 278-287, 2000.								
	AW	2000-306859, published November 2, 2000.							
	AX	M. NAKATA, et al., "TWO-DIMENSIONALLY POSITION-CONTROLLED ULTRA-LARGE GRAIN GROWTH BASED ON PHASE-MODULATED EXCIMER-LASER ANNEALING METHOD", Department of Physical Electronics, Tokyo Institute of Technology, Electrochemical Society Proceedings, Vol. 2000-31, pgs. 148 – 154.							
	AY	Wen-Chang YEH, et al., "EFFECTS OF A LOW-MELTING-POINT UNDERLAYER ON EXCIMER-LASER-INDUCED LATERAL CRYSTALLIZATION OF SI THIN-FILMS", Jpn. J. Appl. Phys. Vol. 40 (2001), Part 1, No. 5A, May 2001, pp. 3096 - 3100							
	AZ	Y. SANO, et al., "HIGHLY PACKED AND ULTRA-LARGE SI GRAINS GROWN BY A SINGLE-SHOT IRRADIATION OF EXCIMER-LASER LIGHT PULSE", Department of Physical Electronics, Tokyo Institute of Technology,						sheet(s) attached	
(8 pages) Examiner						Date Considered			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.									